Applicant(s)/Patent Under Application/Control No. Reexamination 10/757,182 BAIG ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2112 **Enam Ahmed U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY * 714/704 US-6,871,304 03-2005 Hadjihassan et al. Α 714/705 * 08-2001 Ransijn, Johannes Gerardus US-6,275,959 В 375/287 * US-5,521,941 05-1996 Wiatrowski et al. С US-D US-E F US-US-G US-Н US-1 US-J US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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